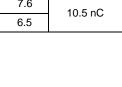
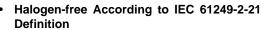


N-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
60	0.025 at V _{GS} = 10 V	7.6	10.5 nC			
00	0.035 at V _{GS} = 4.5 V	6.5	10.5110			

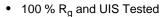










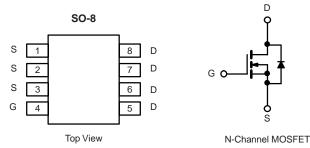






APPLICATIONS

CCFL Inverter



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V_{DS}	60	V		
Gate-Source Voltage		V_{GS}	± 20	v	
	T _C = 25 °C		7.6 ^a		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		6.8		
Continuous Diairi Current (1) = 150 °C)	T _A = 25 °C	I _D	6.1 ^{b, c}		
	T _A = 70 °C		4.8 ^{b, c}		
Pulsed Drain Current	I _{DM}	25	A		
Continuous Course Davis Diada Courset	T _C = 25 °C		4.2		
Continuous Source-Drain Diode Current	T _A = 25 °C	ls -	2.1 ^{b, c}		
Avalanche Current	1 0411	I _{AS}	15		
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	11.2	mJ	
	T _C = 25 °C		5		
Mavinous Deven Dissipation	T _C = 70 °C	P _D	3.2	W	
Maximum Power Dissipation	T _A = 25 °C	FD —	2.5 ^{b, c}	vv	
	T _A = 70 °C		1.6 ^{b, c}		
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	20	25	C/VV	

Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	-		L		l.		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 250		55		\//00	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.3		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Vallana Busin Oursel	1	V _{DS} = 60 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V, T _J = 55 °C			10	10 µA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25			Α	
2	_	$V_{GS} = 10 \text{ V}, I_D = 4.6 \text{ A}$		0.025		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4.2 \text{ A}$		0.035			
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, I_{D} = 4.6 \text{ A}$		20		S	
Dynamic ^b				•			
Input Capacitance	C _{iss}			1100		pF	
Output Capacitance	C _{oss}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		90			
Reverse Transfer Capacitance	C _{rss}			55			
Total Oats Observe	0	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 4.6 \text{ A}$		21	32	0	
Total Gate Charge	Q_g			10.5	16		
Gate-Source Charge	Q_{gs}	$V_{DS} = 30 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 4.6 \text{ A}$		3.5		nC	
Gate-Drain Charge	Q_{gd}			4.2			
Gate Resistance	R _g	f = 1 MHz		3.3	5	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	ì,	$V_{DD} = 30 \text{ V}, R_{L} = 5.4 \Omega$		150	225		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5.6 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		20	30		
Fall Time	t _f			60	90		
Turn-On Delay Time	t _{d(on)}			10	15	ns	
Rise Time	t _r	$V_{DD} = 30 \text{ V, R}_{L} = 5.4 \Omega$		15	25		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5.6 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		25	40		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characterist	ics						
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			4.2	^	
Pulse Diode Forward Current ^a	I _{SM}	-			25	Α	
Body Diode Voltage	V _{SD}	I _S = 2 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	-		25	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 FFA 41/44 400 A/4- T 0500		25	50	nC	
Reverse Recovery Fall Time		$I_F = 5.5 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 \text{ °C}$ t_b		19		_	
Reverse Recovery Rise Time				6		ns	

Notes:

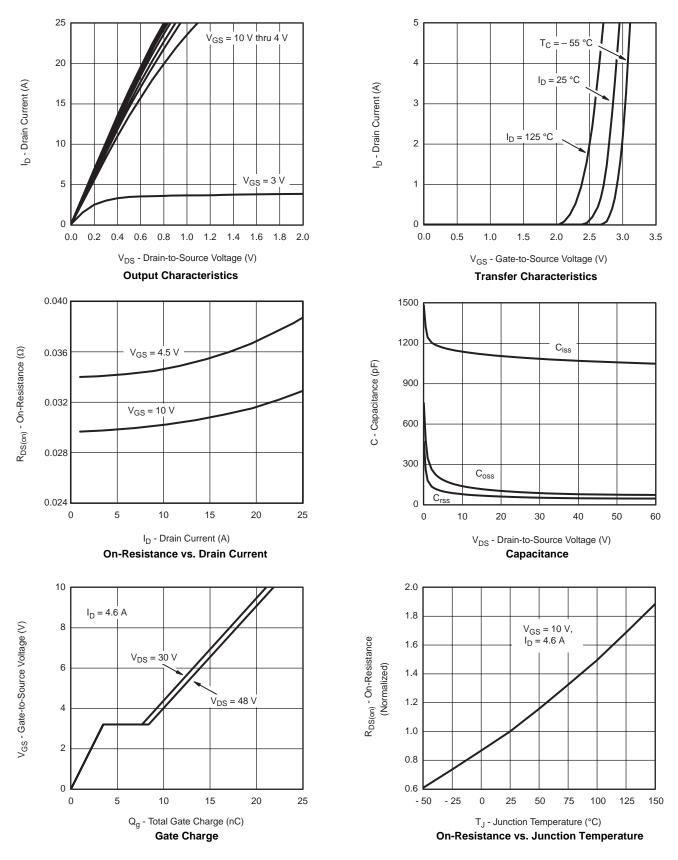
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

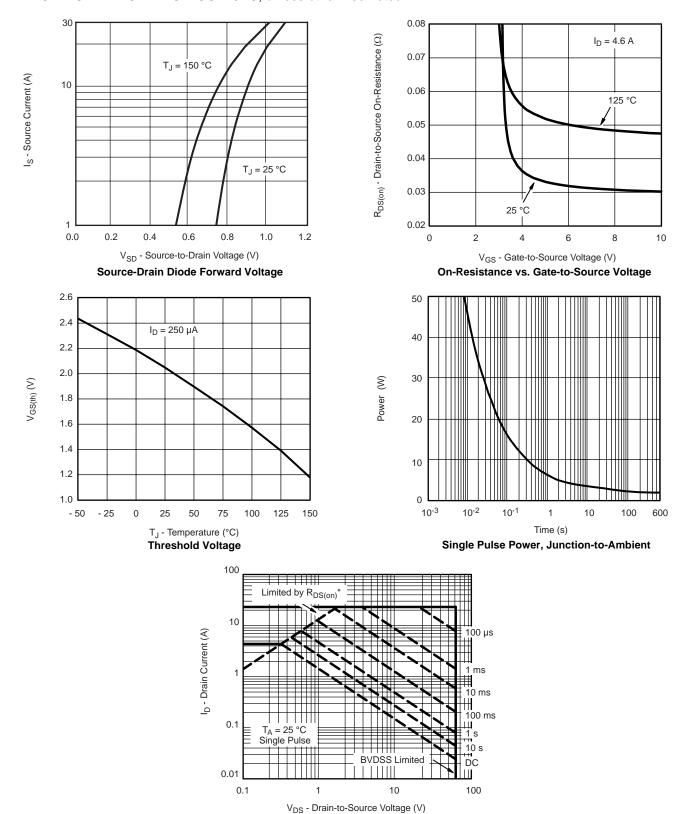


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

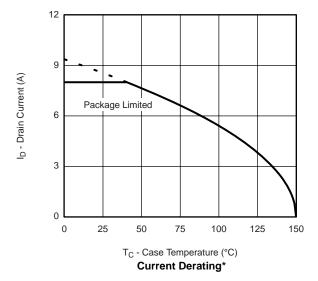


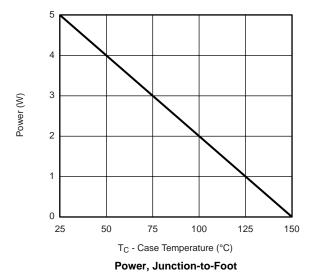
服务热线:400-655-8788 4

* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified **Safe Operating Area**



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



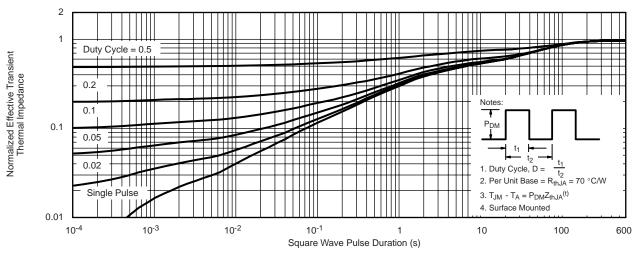


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

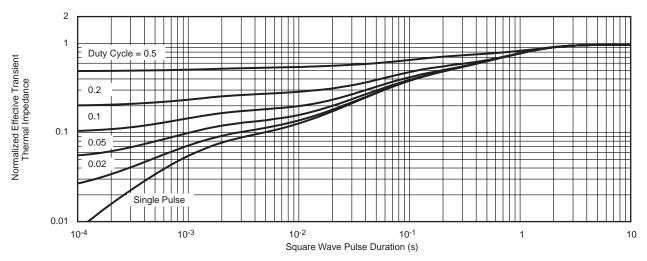


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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient

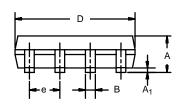


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







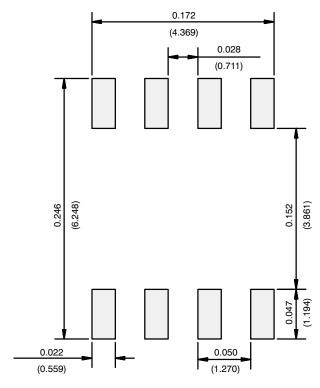
	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pey 11-Sep-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

服务热线:400-655-8788

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